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Overview

- New sublimation technique controls thickness of matrices precisely.
- The sublimation technique is combined with a new MALDI-TOF/TOF MS.
- \bullet Analysis at 10 μm spatial resolution is conducted in both MS and MS/MS.
- Resolving power in MS/MS, up to 10,000, is utilized to visualize distinctive images.
- Classification of obtained images in similarity is performed by a software.

Introduction

Sublimation technique for coating matrices is known to generate highly uniform and fine crystals of matrices, which enables to visualize precise distribution of targeted molecule in MALDI imaging. A thickness of coated matrix is necessary to be controlled to achieve high reproducibility. However, controlling the thickness is frequently hard, because it is managed only by elapsed time of sublimation. Measuring increased weight of the coated subject is reliable, but it should be done after coating. Recently, we developed a new sublimation technique, in which the thickness of matrix is monitored in real time by variation of laser light transmission. We will report an experimental condition of the sublimation technique for MALDI imaging and apply it to a new vacuum MALDI-TOF/TOF.

Methods Condition for Sublimation

Sample	: mouse cerebellum
Instrument	: iMLayer (Shimadzu Corp.)
Matrices	: 9-AA, DHB
Thickness of matrix	: 1 to 4um, monitored by variation of laser light transmission
Recrystallization ³⁾ was conducted following the sublimation.	



MALDI-tandem TOFMS

Instrument: MALDI-7090 (Shimadzu/Kratos)Measurement: High-energy CID-MS/MS in positive ion mode.Collision gas: heliumCollision energy: 20 keV (laboratory frame of reference).





Principle of Axial Spatial Distribution Focusing (ASDF)

MS/MS resolution is improved with correcting the spatial distribution of ions in ASDF cell. This is achieved by applying a pulsed electrostatic field at the point, at which the precursor and fragments are velocity focussed but are spatially resolved.

Statistical analysis

Imaging MS Solutions (Shimadzu Corp.) was applied to visualize all images and to classify them in similarity.



Fig.2 Axial Spatial Distribution Focusing



Results

Unit for thickness measurement



Features

- Fine crystal size
- Control of matrix layer thickness
- Automated procedure
- Compact size, enough to be installed in a fume hood.

Fig.3 Principle of iMLayer



Fig.4 Thickness and amount of matrices





MS image of the m/z indicated with arrows in the spectrum below.



Optical image of the tissue

Fig.5 MS imaging of cerebellum at 10µm spatial resolution





Fig.6 MS/MS imaging at 10µm spatial resolution

m/z 605; fragment ion



Merged view of *m/z* 772 & 605





Optical image of the tissue



Optical image of the tissue



Green: *m/z* 184 Red: *m/z* 649 Blue: *m/z* 772

Merged view of MS/MS imaging





Comparison of MS/MS spectrum between PC(16:0/16:0)+K and m/z 772 in the tissue.





Fig.8 MS/MS imaging at 30µm spatial resolution (Precursor: *m/z* 798)



Conclusions

- High reproducibility of sublimation was obtained by monitoring the thickness of matrices in real time.
- The sublimation technique and the new MALDI-TOF/TOF was optimum combination, especially, to have high quality MS/MS imaging in terms of reproducibility and high spatial resolution.
- Well-resolved signals at both precursor region and fragment ions by ASDF can be utilized to visualize distinctive images so clearly that they are classified in similarity using statistical analysis.

References

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